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IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

Priority Application Serial No. .... 10/057,711  
Priority Filing Date ..... January 24, 2002  
Inventor ..... Warren M. Farnworth et al.  
Assignee ..... Micron Technology, Inc.  
Priority Group Art Unit ..... 2829  
Priority Examiner ..... R. Kobert  
Attorney's Docket No. .... MI22-2379  
Title: Method and Apparatus for Testing Semiconductor Circuitry for Operability  
and Method of Forming Apparatus for Testing Semiconductor Circuitry for  
Operability

**PRELIMINARY AMENDMENT**

To: Mail Stop PATENT APPLICATION  
Commissioner for Patents  
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Sir:

This is a preliminary amendment accompanying a Request for Divisional Application for the above-entitled patent application. Prior to examining the application, please enter the following amendments.

**AMENDMENTS**

Underlines indicate insertions and ~~strikeouts~~ indicate deletions.